Δ		œ	v	٠,		٠,		×	×	٠,	٠,	v	٠,	×	٠,	v	×	×	×	0	×	٠,	٠,	v	0	×	٠,	٠,	٠,	٠,	×	٠.	3

Notice of References Cited

Application/Control No. 10/736,944	Applicant(s)/Pater Reexamination CHU ET AL.	nt Under
Examiner	Art Unit	
Ljiljana (Lil) V. Ciric	3753	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,205,798	03-2001	Porter et al.	62/129
*	В	US-6,549,857	04-2003	Fierro et al.	702/51
*	С	US-6,629,450	10-2003	Lu et al.	73/40
*	D	US-6,720,882	04-2004	Davey, Kenneth John	73/40
*	Е	US-7,000,467	02-2006	Chu et al.	73/299
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	J	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.